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High Resolution Microscopy Resolution Target



High Resolution Microscopy Resolution Target, #37-539

Stock **#37-539** 11 In Stock

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1

+

C\$2,632⁰⁰

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Qty 1-4	C\$2,632.00 each
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Physical & Mechanical Properties

Dimensions (mm):
10 x 10 x 1

Construction:
Stainless Steel, 75 x 25 x 1.5mm, microscope slide format

Pattern:
Pinholes Diameter: 4µm, 2µm, 1µm, 0.5µm, 0.25µm
Line patterns: 58 groups, 7.5 - 3300 lp/mm
Line Widths: 66.7µm - 0.152µm

Pattern Tolerance:

100nm/cm = 10⁻⁵

Optical Properties

Substrate:

Fused Silica w/Chrome deposit

Optical Density OD (Average):
OD>7 @ 400nm, 6 @ 550nm, 4.5 @ 750nm, 3.6 @ 1000nm

Spectral Range:

200 - 2000nm

Regulatory Compliance

RoHS 2015:

Compliant

Certificate of Conformance:

View

Reach 233:

Compliant

Product Details

- Small Pattern Sizes - 100nm and 3300 lp/mm
- Composed using High-Precision E-Beam Lithography
- Negative Pattern Design

High Resolution MicroscopySlide Targets are designed using high-precision e-beam lithography. The patterns are etched on a 10 × 10mm² fused silica substrate with broad spectral transmission (DUV-VIS-NIR), on which a chromium layer of high optical densityis applied. Byremoving the chromium layer, patterns are created in sizes down to 100nm. High Resolution MicroscopySlide Targets provide excellent dimensional stability and are mounted in a metal microscope slide holder. The negative patterns on each target allow the structures to be transparent, while the background is blocked by a chrome layer.

High Res Microscopy USAF Target

High Res Microscopy USAF Targets easily determine the resolution limit of an objective in transmitted light and consists of 59 line patterns with 7.5 to 3300 lp/mm in horizontal and vertical alignment. This target also features 5 pinholes with diameters between 4.0-0.25µm, which allows for detailed characterization of micro-imaging optics.

High Res Microscopy Star Target

High Res Microscopy Star Targets consist of 5 Siemens stars and show the peculiarity that the tapered segments in the center of the stars are precisely manufactured to a minimum width of 150nm. This target is ideal for the determining the resolution of microscope objectives with very high numerical apertures.

High Res Microscopy Checker Board

High Res Microscopy Checker Board features a total size of 9.0 x 9.0mm² out of 50 x 50µm² squares. The checker board is ideal for testing of image skew and curvature, along with determining image quality due to the straight and sharp edges.